Product/Process Change Notice - PCN 19_0135 Rev. -

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This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. **Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date.** ADI contact information is listed below.

PCN Title: LTC6811-1, LTC6811-2 Die Revision Change.

Publication Date: 25-Jun-2019

Effectivity Date: 27-Sep-2019 *(the earliest date that a customer could expect to receive changed material)*

Revision Description:
Initial Release.

Description Of Change:

Please be advised that Analog Devices has made minor changes to the LTC6811 die.
Two issues are being addressed:
1. On earlier revisions, the DCTO (discharge timeout) readback value is incorrectly reported for a period of up to 100ms immediately after writing the DCTO value. On the new revision, the DCTO readback value is correct immediately after writing.
2. Changes have been made to metal-metal capacitor structures and to metal interconnect routing to improve manufacturability, quality, and reliability. Numerous metal-metal capacitors were changed from lateral capacitors to vertical capacitors. Likewise, metal interconnects throughout the design have been adjusted to increase spacing where possible.

Reason For Change:

To improve manufacturability, quality, and reliability.

Impact of the change (positive or negative) on fit, form, function & reliability:

There is no change in form, fit, & function.

Product Identification *(this section will describe how to identify the changed material)*

The parts that will be assembled with new die will be identified by Date Code.

Summary of Supporting Information:

Qualification has been performed per AEC-Q100, Stress Test Qualification for Integrated Circuits.

Comments

Changes were made using metal layers only. Product specifications are unaffected and the datasheet remains unchanged. The die change was qualified by performing characterization over the full operating junction temperature range and through rigorous engineering evaluation. In addition, the product successfully completed HTOL, ESD, Latchup, and ELFR stress testing.

Supporting Documents

Attachment 1: Type: Delta Qualification Matrix

ADI_PCN_19_0135_Rev_-_LTC6811_RevK_ZVEI.xlsm

Attachment 2: Type: Qualification Results Summary

ADI_PCN_19_0135_Rev_-_LTC6811_PCN_DATA.pdf

Attachment 3: Type: Other

ADI_PCN_19_0135_Rev_-_LTC6811_PCN_ESD.pdf

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.			
Americas: PCN_Americas@analog.com	**Europe:** PCN_Europe@analog.com	**Japan:** PCN_Japan@analog.com	**Rest of Asia:** PCN_ROA@analog.com

Appendix A - Affected ADI Models				
Added Parts On This Revision - Product Family / Model Number (29)				
LTC6811-1 / LTC6811HG-1#3MVPBF	LTC6811-1 / LTC6811HG-1#3MVTRPBF	LTC6811-1 / LTC6811HG-1#3ZXPBF	LTC6811-1 / LTC6811HG-1#3ZXTRPBF	LTC6811-1 / LTC6811HG-1#3ZZPBF
LTC6811-1 / LTC6811HG-1#3ZZTRPBF	LTC6811-1 / LTC6811HG-1#PBF	LTC6811-1 / LTC6811HG-1#TRPBF	LTC6811-1 / LTC6811IG-1#3MWPBF	LTC6811-1 / LTC6811IG-1#3MWTRPBF
LTC6811-1 / LTC6811IG-1#3ZXPBF	LTC6811-1 / LTC6811IG-1#3ZXTRPBF	LTC6811-1 / LTC6811IG-1#3ZZPBF	LTC6811-1 / LTC6811IG-1#3ZZTRPBF	LTC6811-1 / LTC6811IG-1#PBF
LTC6811-1 / LTC6811IG-1#TRPBF	LTC6811-2 / LTC6811HG-2#3ZXPBF	LTC6811-2 / LTC6811HG-2#3ZXTRPBF	LTC6811-2 / LTC6811HG-2#3ZZPBF	LTC6811-2 / LTC6811HG-2#3ZZTRPBF
LTC6811-2 / LTC6811HG-2#PBF	LTC6811-2 / LTC6811HG-2#TRMPBF	LTC6811-2 / LTC6811HG-2#TRPBF	LTC6811-2 / LTC6811IG-2#3ZXPBF	LTC6811-2 / LTC6811IG-2#3ZXTRPBF
LTC6811-2 / LTC6811IG-2#3ZZPBF	LTC6811-2 / LTC6811IG-2#3ZZTRPBF	LTC6811-2 / LTC6811IG-2#PBF	LTC6811-2 / LTC6811IG-2#TRPBF	

Appendix B - Revision History			
Rev	**Publish Date**	**Effectivity Date**	**Rev Description**
Rev. -	25-Jun-2019	27-Sep-2019	Initial Release.